

Spectrometer gratings based on direct-write e-beam lithography

**U.D. Zeitner, T. Flügel-Paul, T. Harzendorf,
M. Heusinger, E.-B. Kley**

Fraunhofer Institut für Angewandte Optik und Feinmechanik
Jena, Germany

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- Electron-beam lithography for grating fabrication
- Examples of astro-gratings:
 - CUBES UV-transmission grating
 - CarbonSat high-resolution gratings
 - Sub- λ structures for ultra-wide-band gratings

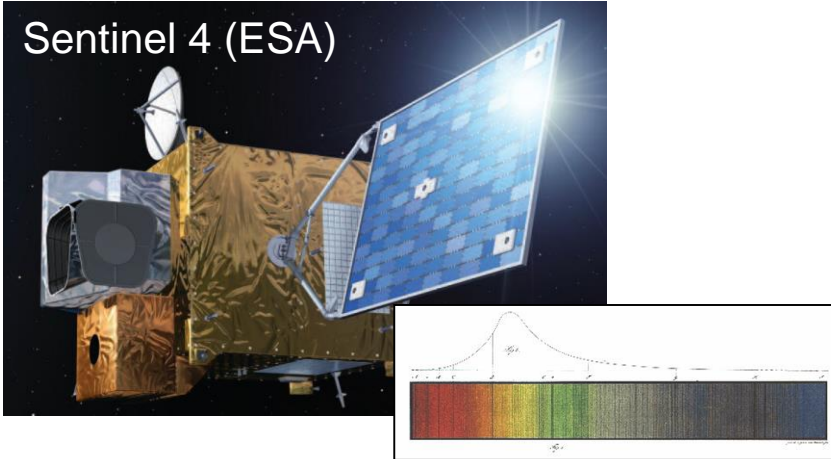
3 μm



High Performance Applications of Gratings

Spectrometers for Astronomy and Earth Observation

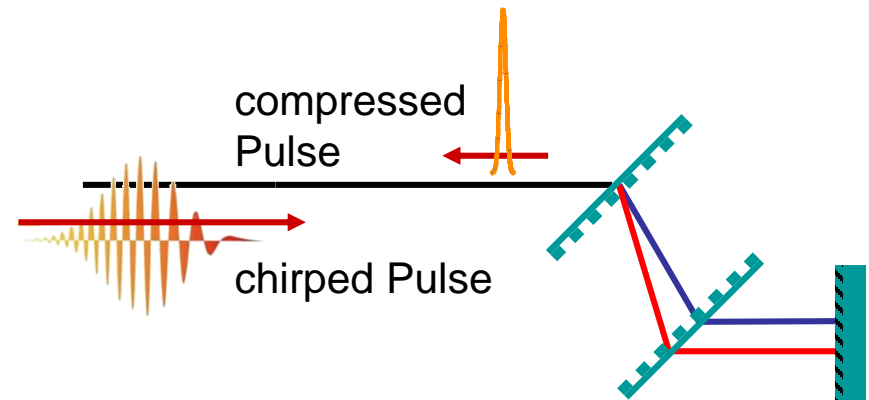
Sentinel 4 (ESA)



relevant parameters:

- spectral dispersion
- bandwidth
- efficiency / polarization
- wavefront
- straylight
- size, ...

Manipulation/Compression of Ultra-Short Laser Pulses

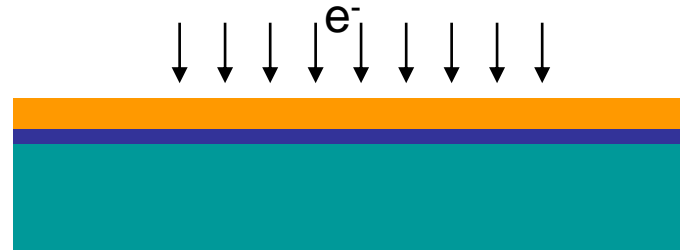


**often extreme demands
to obtain required performance**



Grating Technology at the IOF

1. Resist exposure with e-beam lithography



resist

Cr-layer

SiO₂-Substrate

2. Resist development



3. Chromium etching (RIE)



4. Deep etching into substrate (ICP)



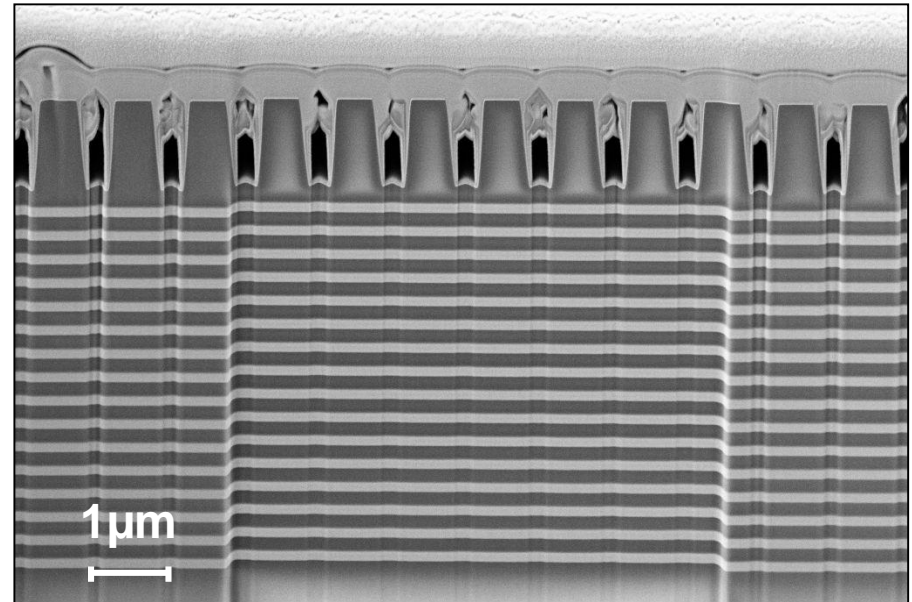
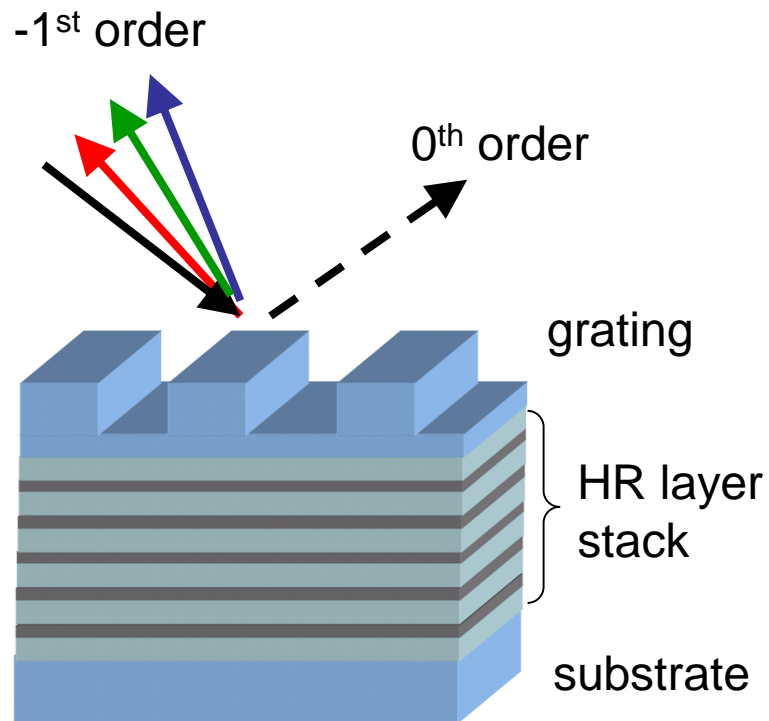
5. Removal of Cr-layer



optional:
multiple iterations
of the process for
multi-level elements



Gratings on dielectric layer stacks

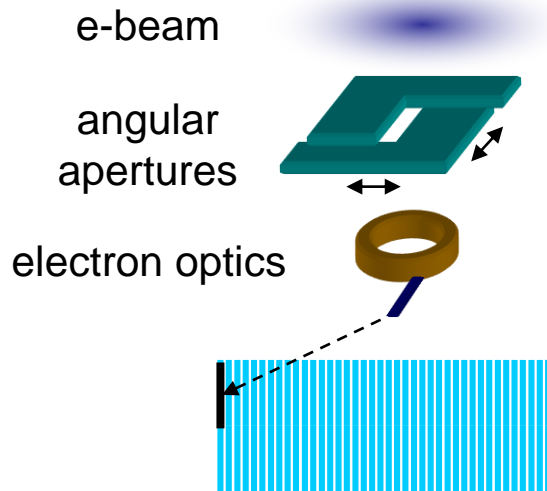


- highly efficient reflection gratings
- transmission gratings with tailored polarization properties



The Vistec SB350 OS e-beam writer

max. writing field: 300mm x 300mm
max. substrate thickness: 15mm
resolution (direct write): <50nm
address grid: 1nm
stitching error: < 12nm P-V / < 2.2nm RMS
placement error: < 14nm P-V
writing strategy: variable shaped beam / cell projection



**very fast
writing process!**

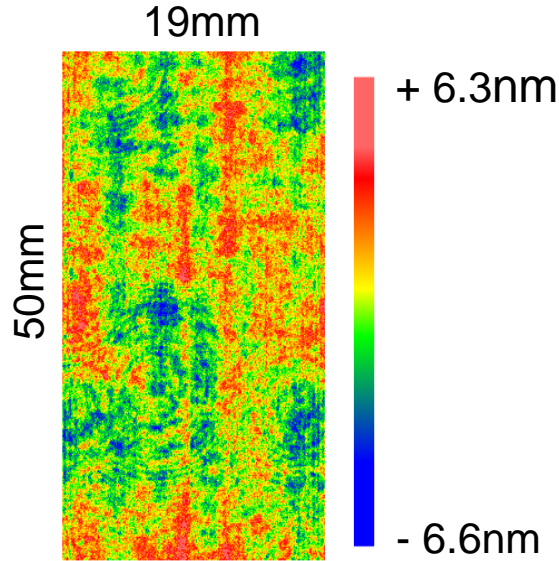
**huge flexibility to
tailor the structure
parameters!**

SB350 OS
(Vistec)



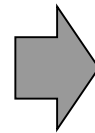
Key Performance: Writing Accuracy

wave-front measurement
(1 μ m period grating + technology, Littrow-Mount)



	wavefront	placement
PV	12.8nm	<10.3 nm
rms	1.4nm	<1.1 nm

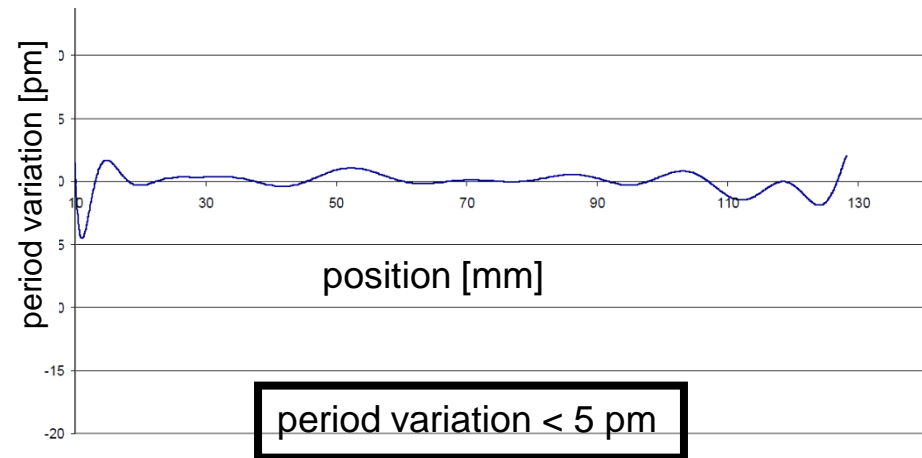
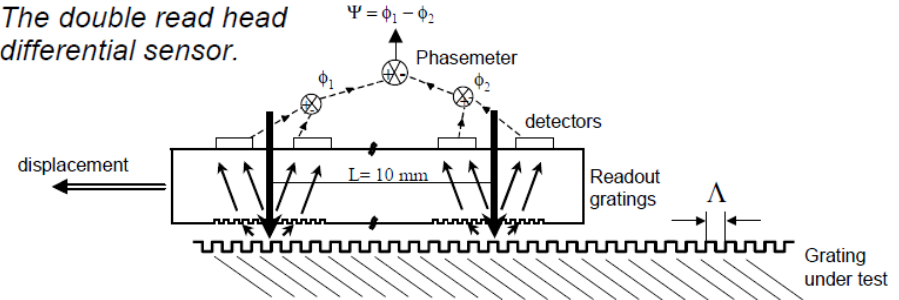
Applications requiring
this accuracy



- Asphere-Test CGH
- Puls compression gratings
- Spectrometer gratings (space application)

Report on the grating writing analysis Laboratoire Hubert Curien CNRS - Fraunhofer IOF

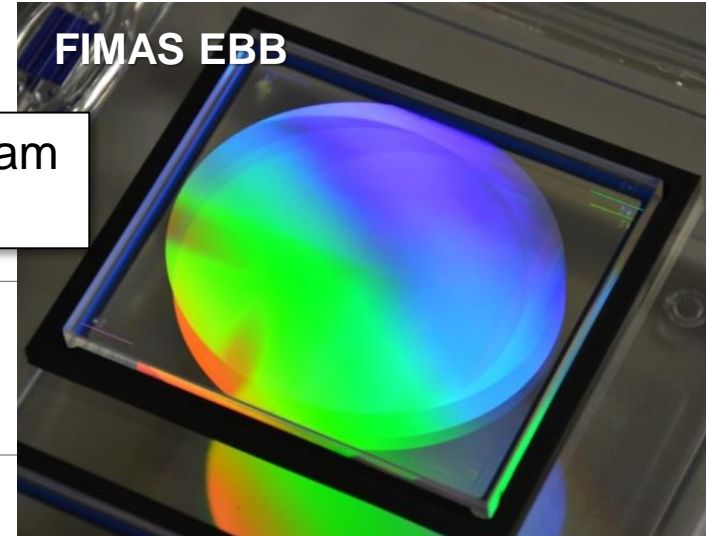
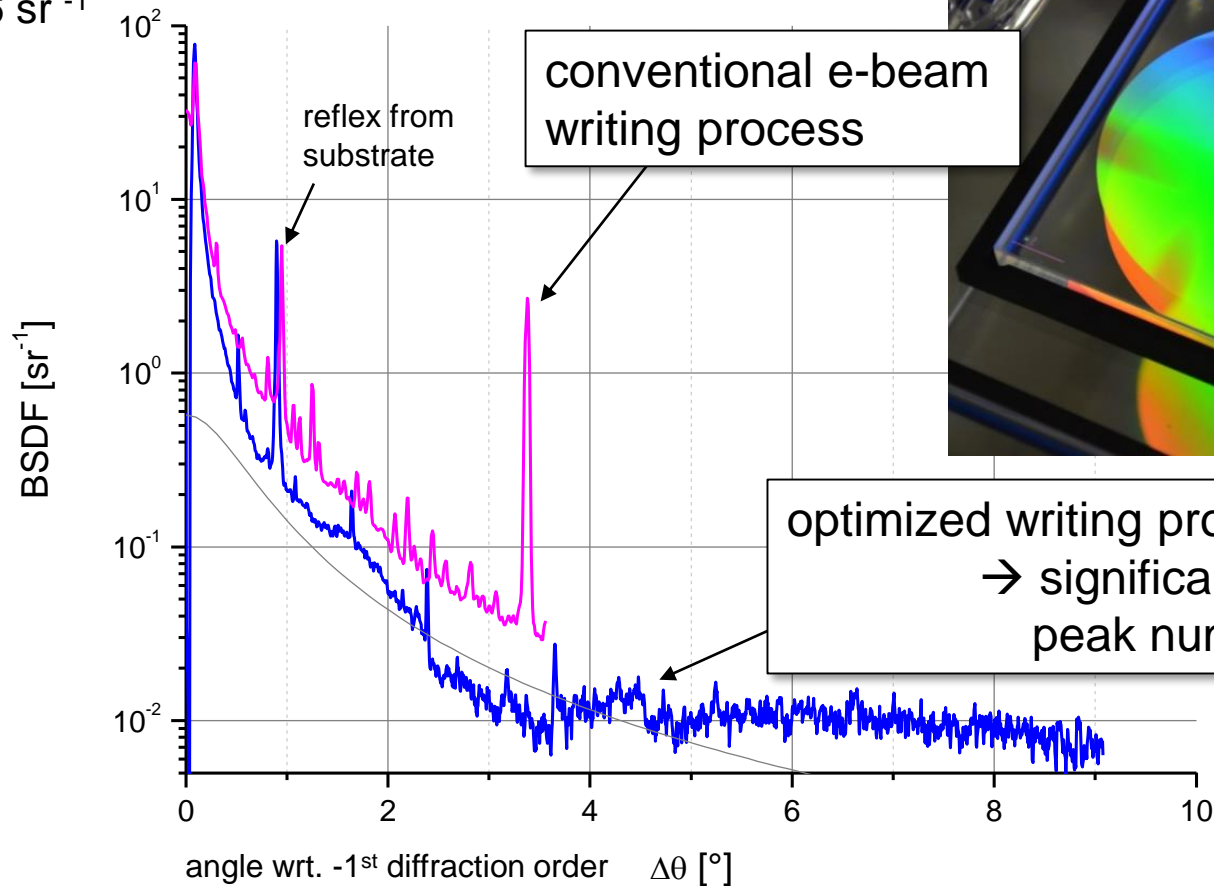
The double read head
differential sensor.



Accuracy of writing process: straylight

Optimization of e-beam writing process

BSDF of -1st DO:
51526 sr⁻¹



optimized writing process
→ significant reduction of
peak number and intensity



Examples of realized spectrometer gratings



CUBES – UV Transmission Grating

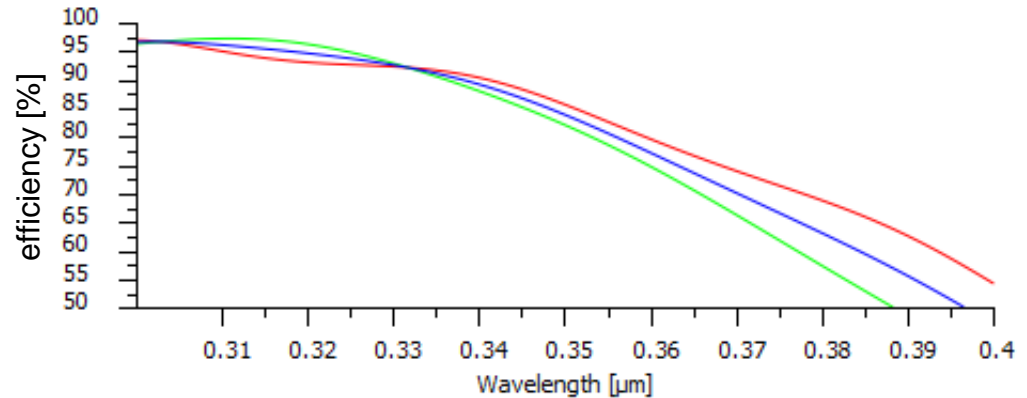
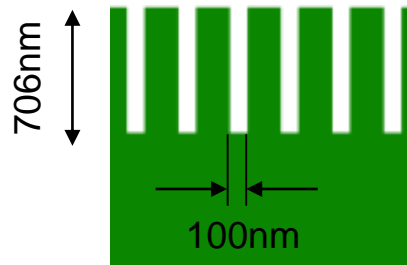
- CUBES (Cassegrain U-Band Brazilian ESO-Spectrograph)
- Requirements:
 - spectral band: **300nm – 400nm**
 - line density: 3448 lines/mm → **p=290nm**
 - AOI: 31°
 - grating size: 250 x 250 mm² ; mosaic of 2x [250mm x 130mm]
- Challenges:
 - **commercial VPH gratings difficult in the UV**
- Solution:
 - **Binary fused silica gratings**



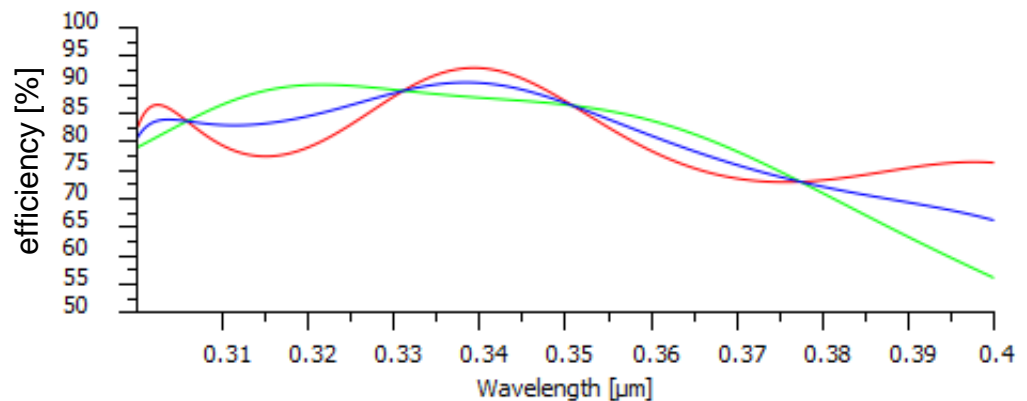
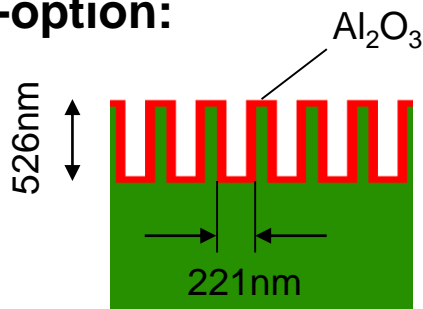
ESO Cubes Spectrometer

Grating parameters: wavelength: 300nm ... 400nm
period: 290nm

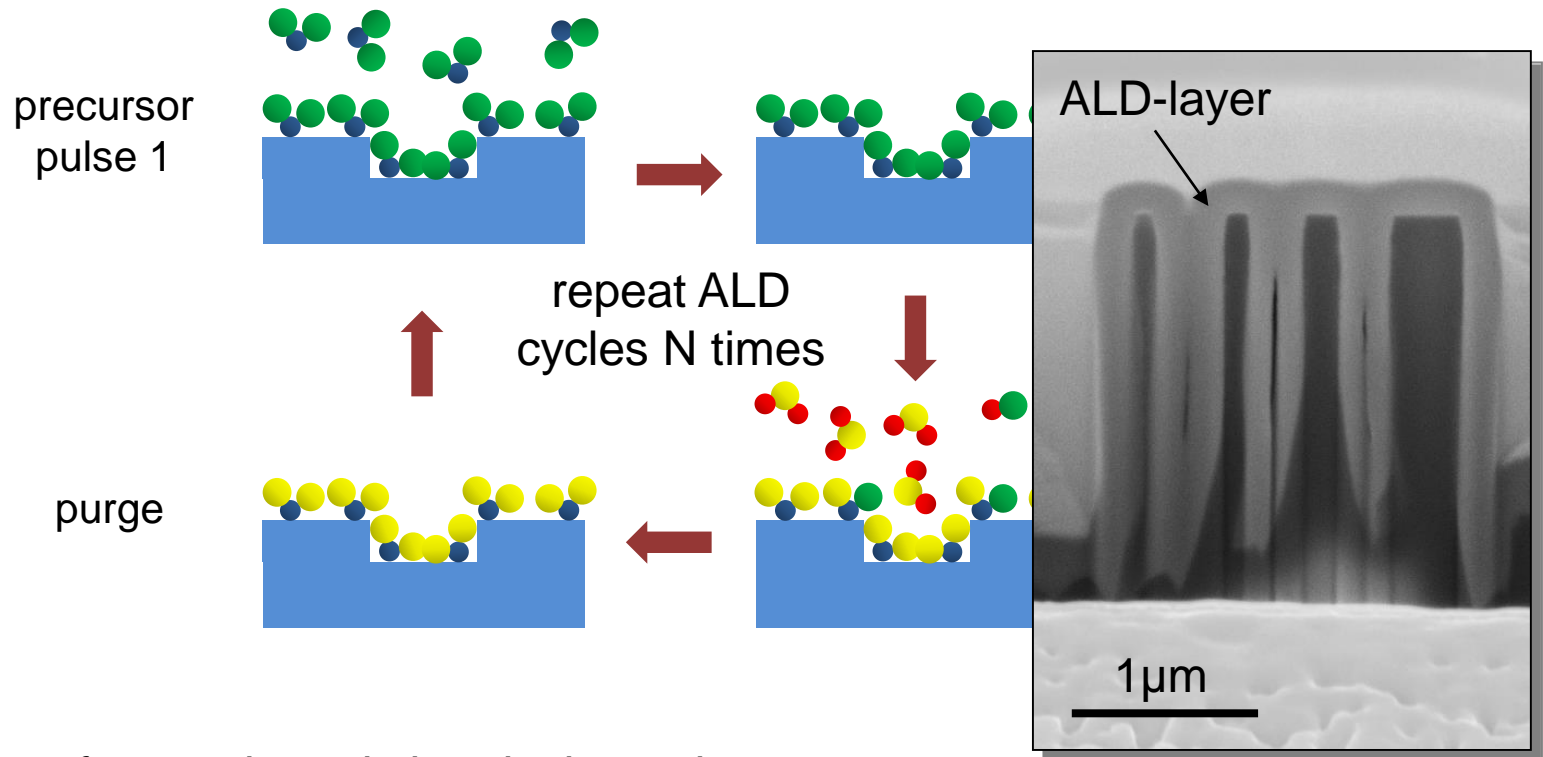
SiO₂-option:



ALD-option:



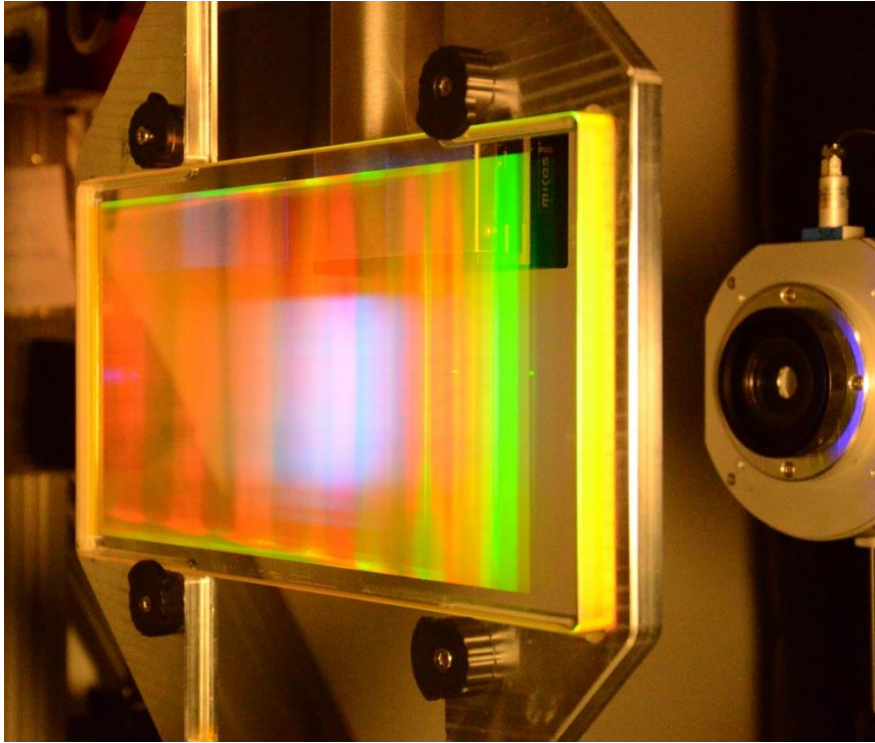
Atomic-Layer-Deposition (ALD)



- surface activated chemical reactions
- **conformal overcoating** of surface reliefs
- large number of materials possible, e.g. TiO_2 , Ta_2O_5 , Al_2O_3 , HfO_2 ...

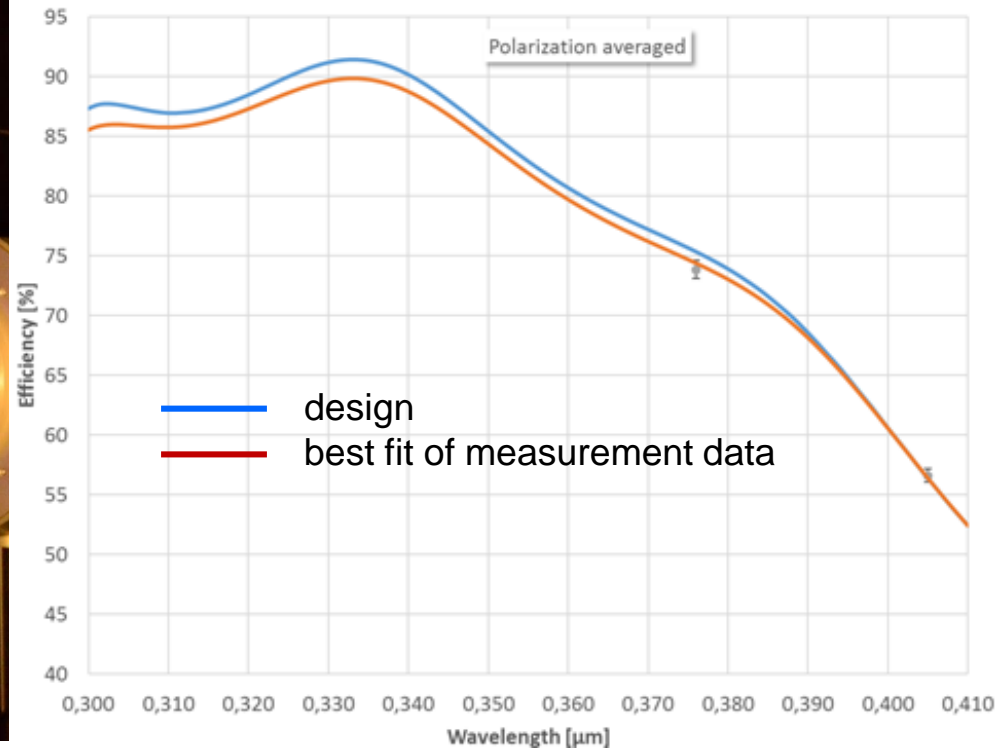


CUBES – UV Transmission Grating



realized grating during efficiency measurement

grating size: 250mm x 130mm



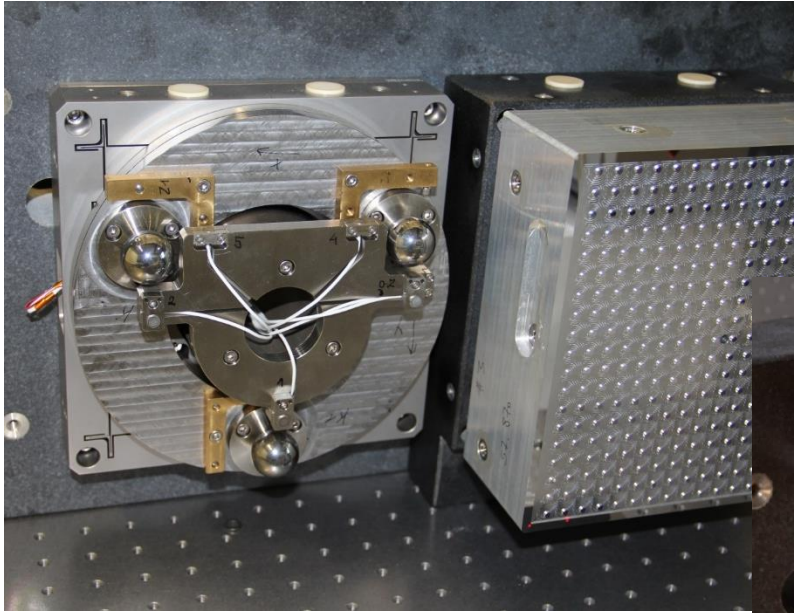
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Fraunhofer
IOF



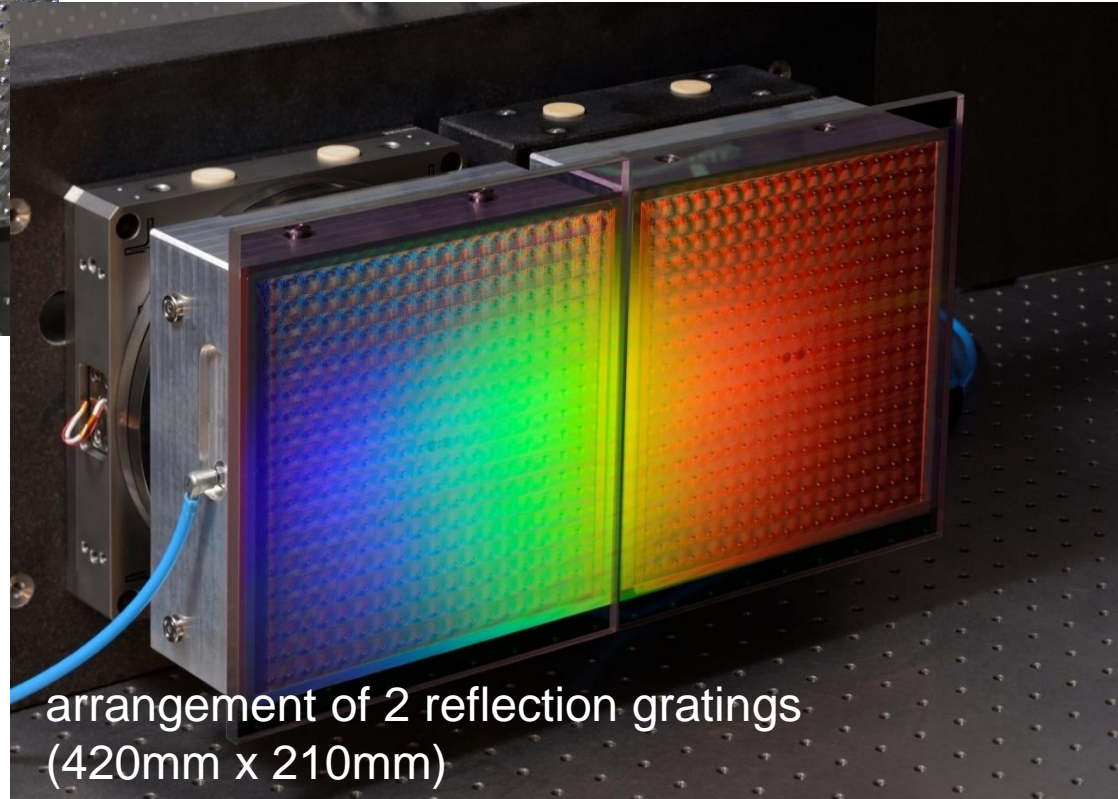
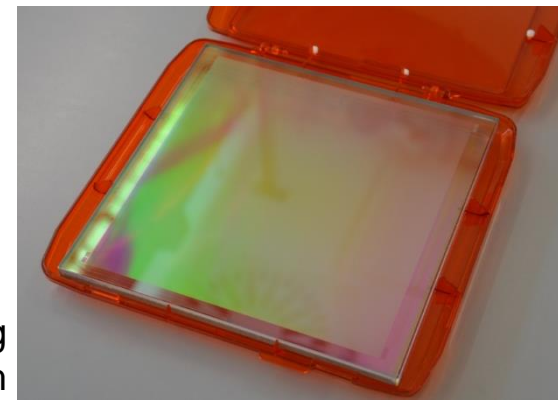
Tiling for Larger Gratings



active alignment for
wave-front optimization

→ also possible for
transmission gratings

single grating
210mm x 210mm

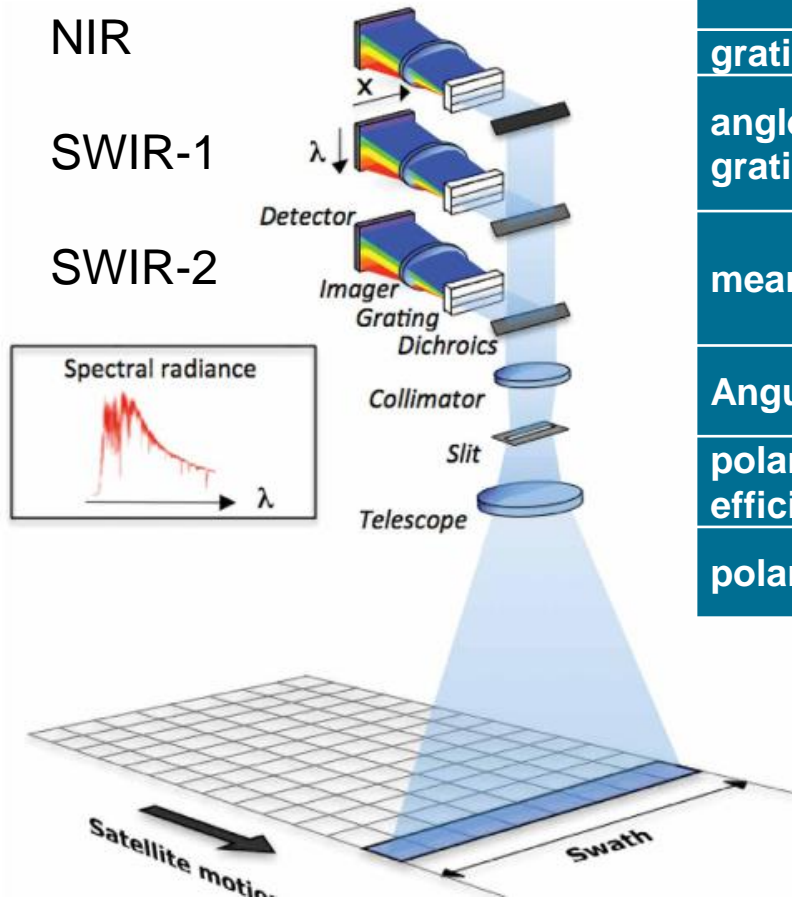


arrangement of 2 reflection gratings
(420mm x 210mm)



Carbon Monitoring Satellite (CarbonSat)

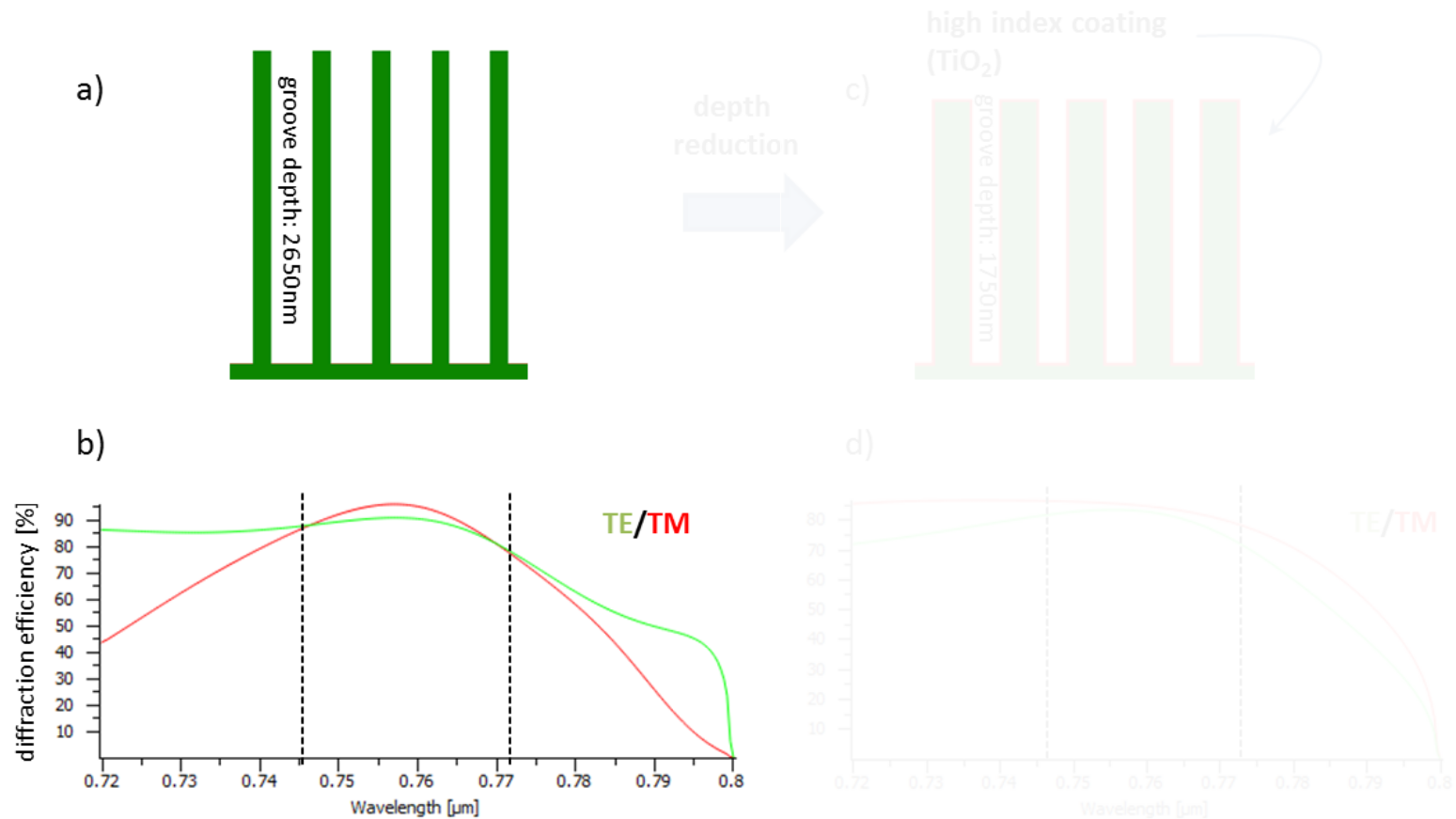
instrument concept:



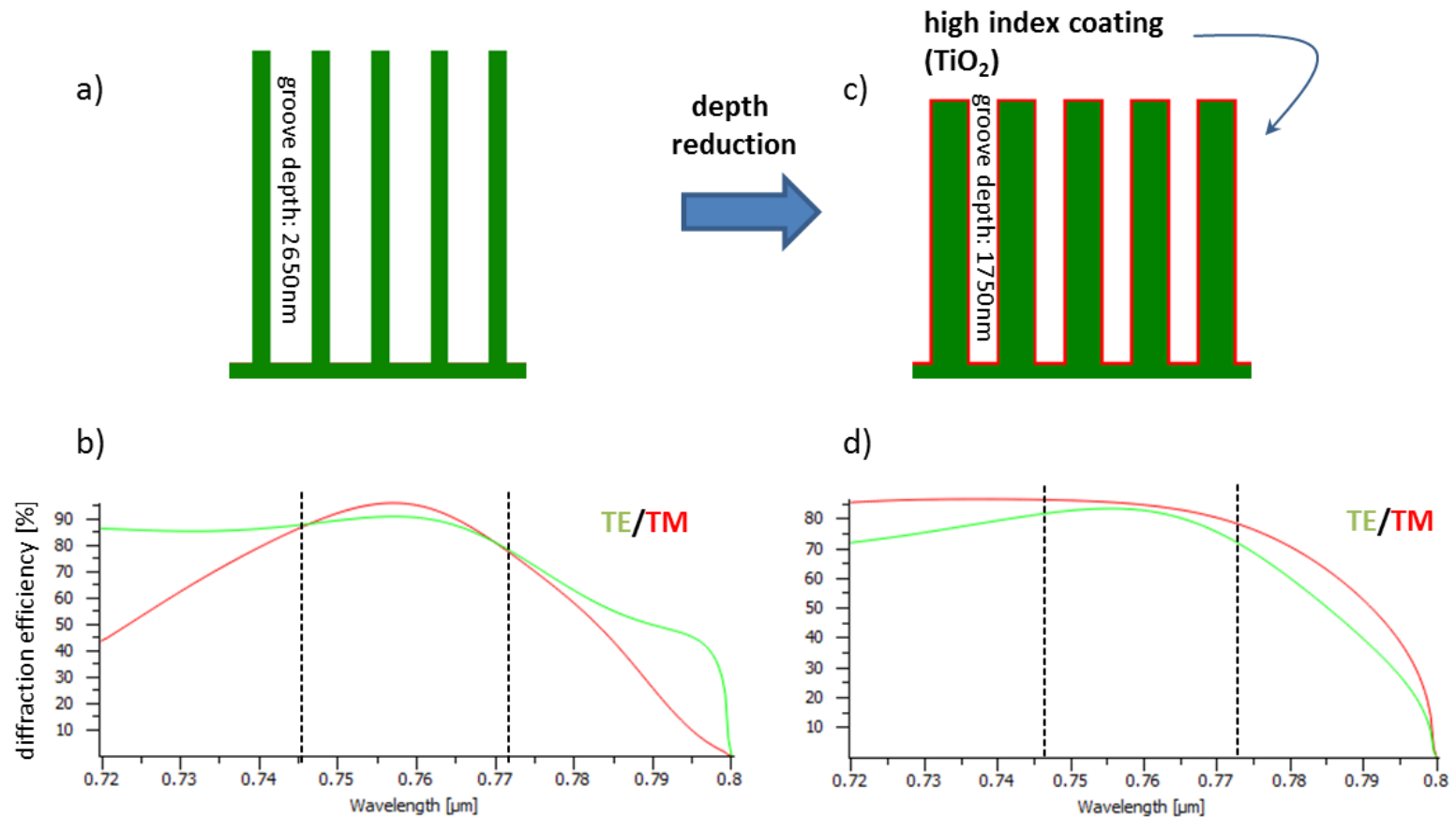
Parameter	NIR	SWIR-1
wavelength	747nm ...773nm	1590nm ...1675nm
grating period	423nm	991nm
angle of incidence to the grating (equivalent in air)	63.6°	55.5°
mean angle of diffraction	Transmission Gratings in -1. order Littrow configuration	
Angular dispersion	0.3° / nm	0.1°/nm
polarization avg. efficiency	>70%	>70%
polarization sensitivity	<10%	<10%




NIR – High Resolution Transmission Grating



NIR – High Resolution Transmission Grating

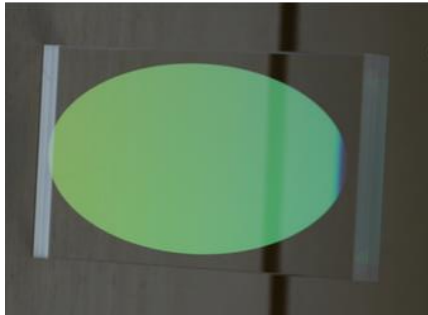
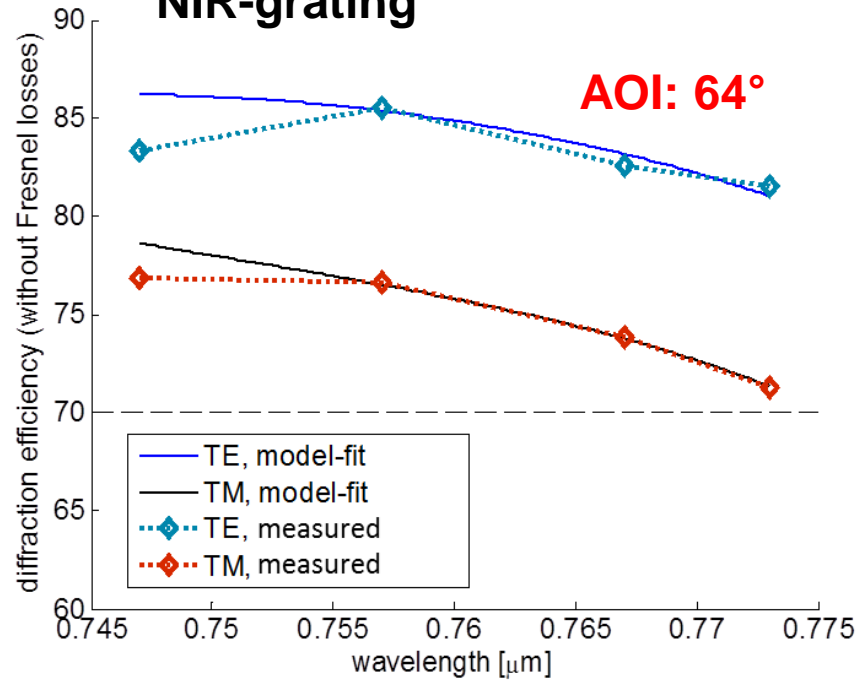


 use high-refractive-index (dielectric) coating to reduce depth



Optical Performance

NIR-grating

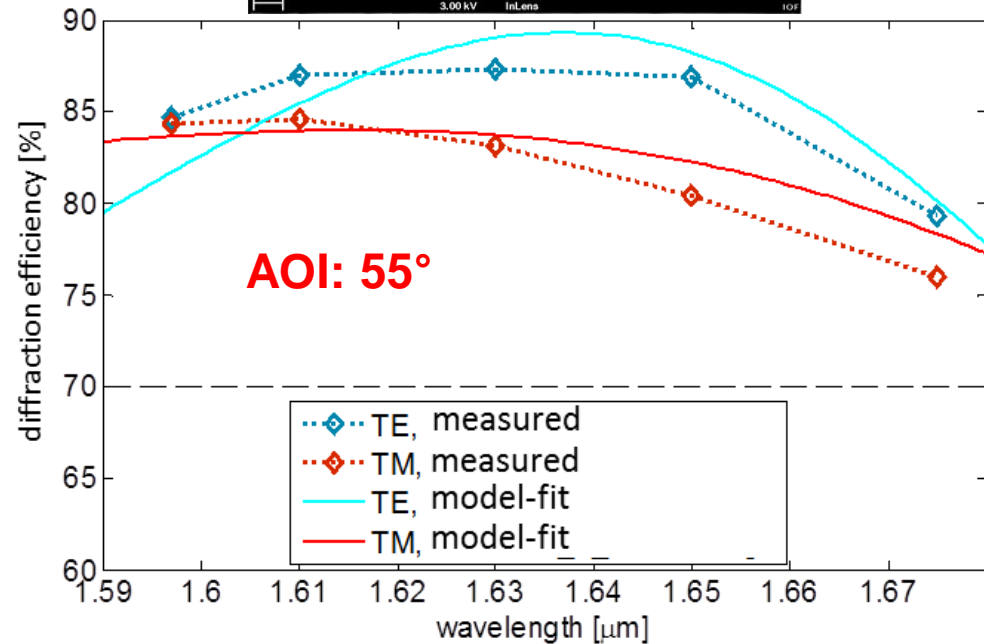
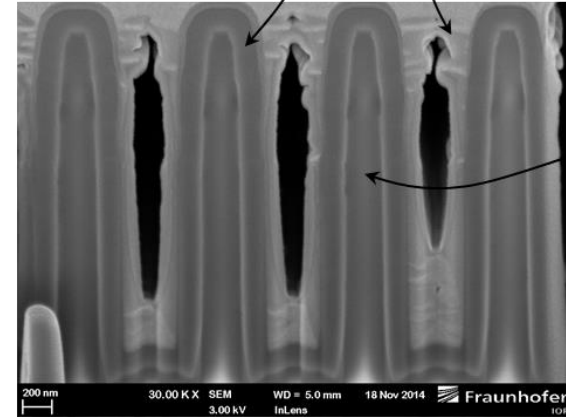


SWIR-1-grating

nanolaminate coating

platinum
(for FIB preparation)

fused silica



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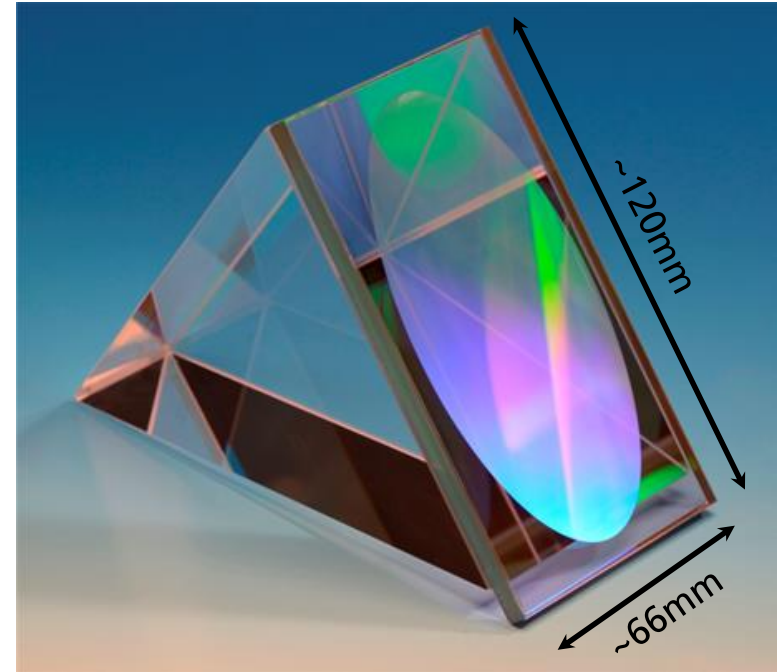
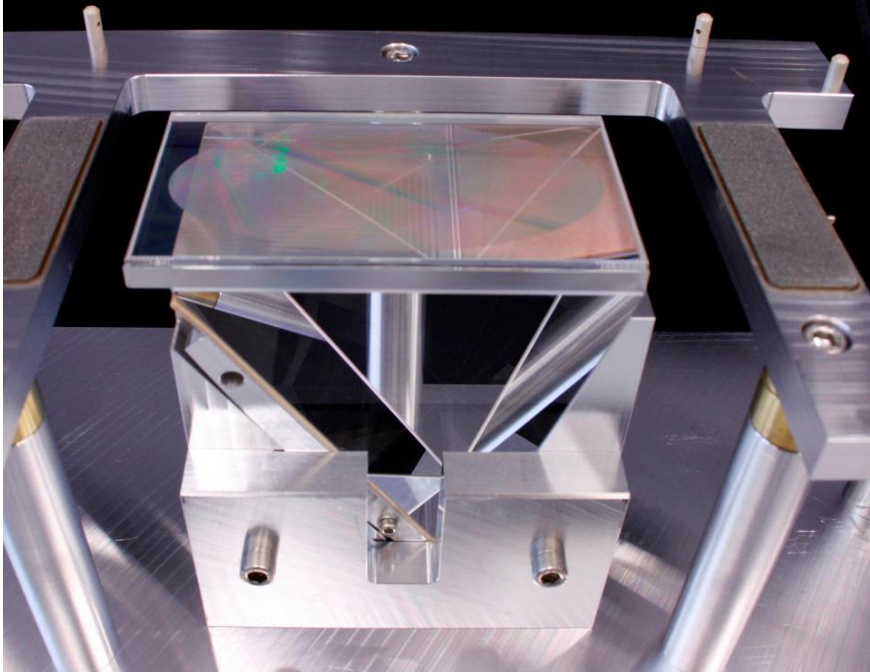


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Direct Glass-to-Glass Bonding

Advantages: adhesive free glass-to-glass connection
no additional optical interface



- achieved alignment accuracy: 0.25mrad (< 1 arcmin)
- **bond strength up to 2/3 of bulk fused silica**
- current TRL: 6



Wide-Band Gratings

- typical requirements for a low-resolution, broad-band disperser
 - spectral range: several 100nm
 - AOI: near-perpendicular incidence
 - period: few μm

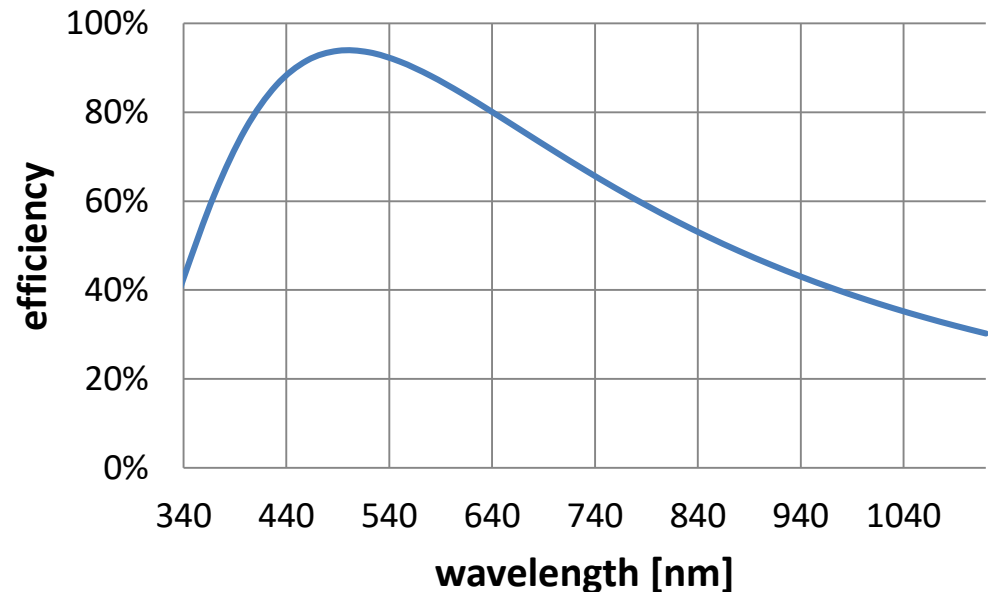


***classical
approach***

- blazed-grating in low order (saw-tooth profile)



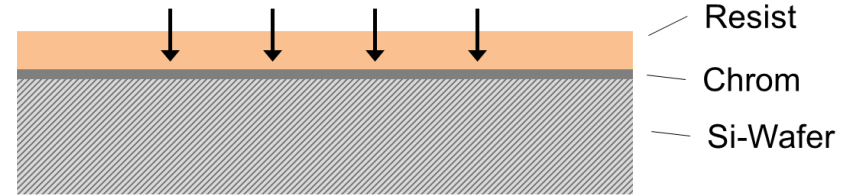
Blaze-Grating



Echelle or Echellette Structures

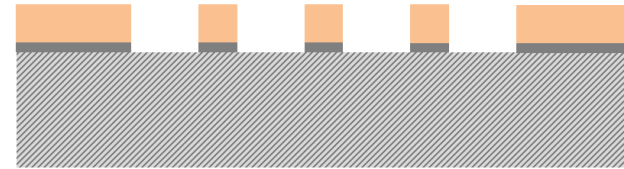
Electron Beam Lithography

①



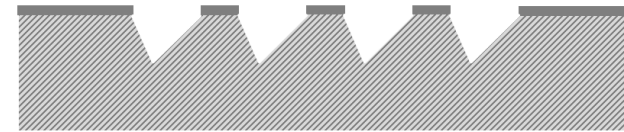
Ion Beam Etching of Mask

②



Wet Chemical Etching of Silicon

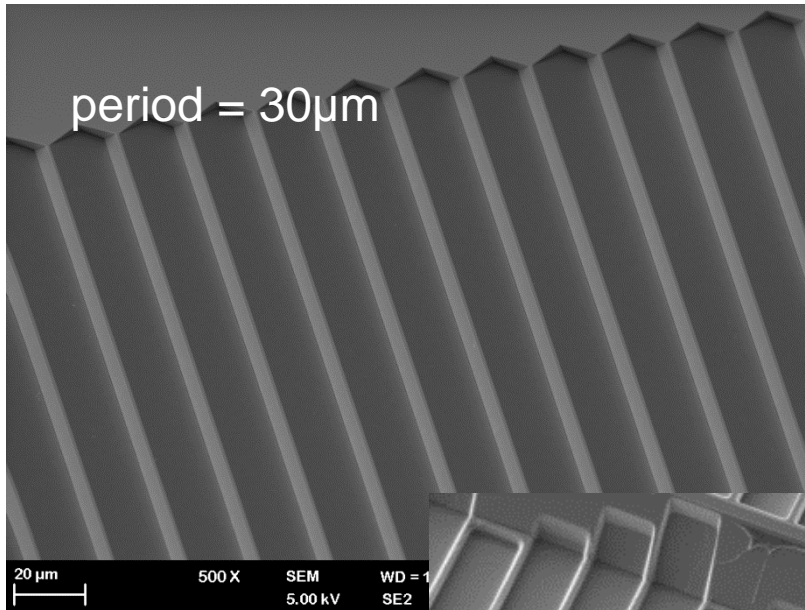
③



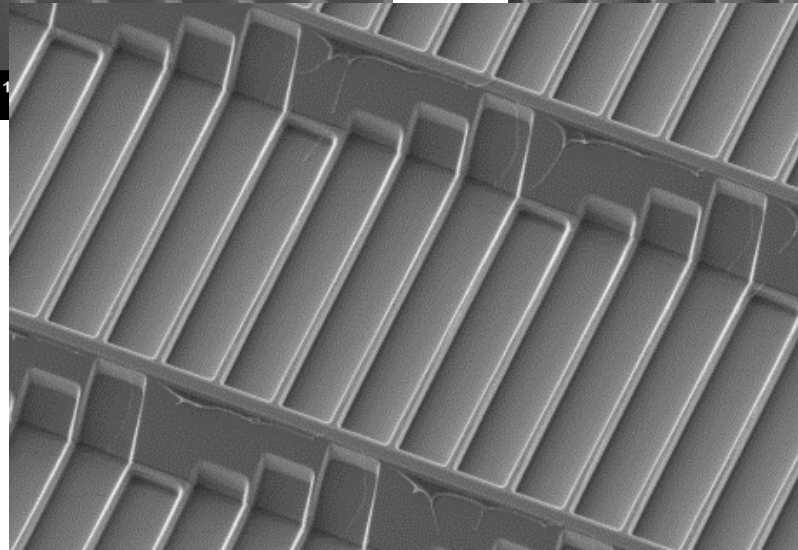
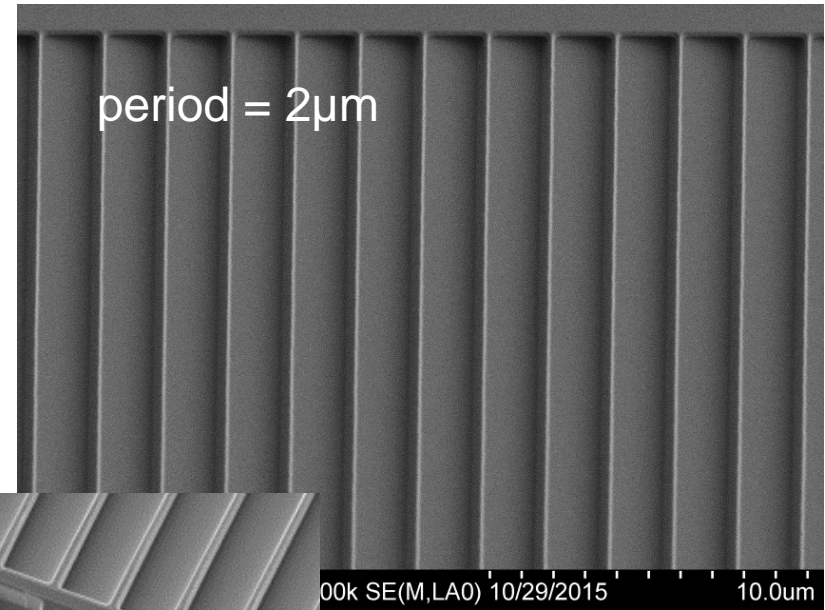
„Blaze Angle“ can be adjusted by crystalline orientation of Silicon substrate



Echelle or Echellette Structures



also lower line
densities possible



integrated cross-
dispersion grating
by direct-write
structuring

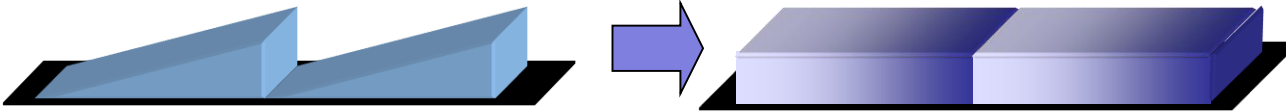


Alternative: Effective Index Gratings

→ sub-wavelength pattern with varying fill factor

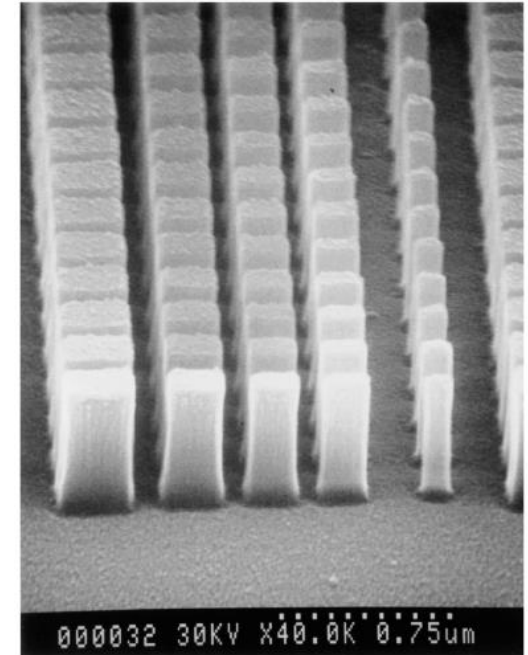
blazed grating

local effective index



sub-wavelength structures

local fill-factor variation



Ph. Lalanne et al. 1998

Advantages:

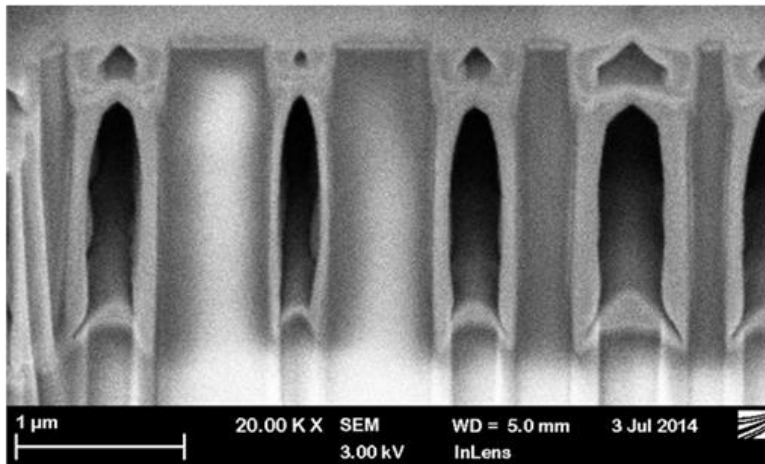
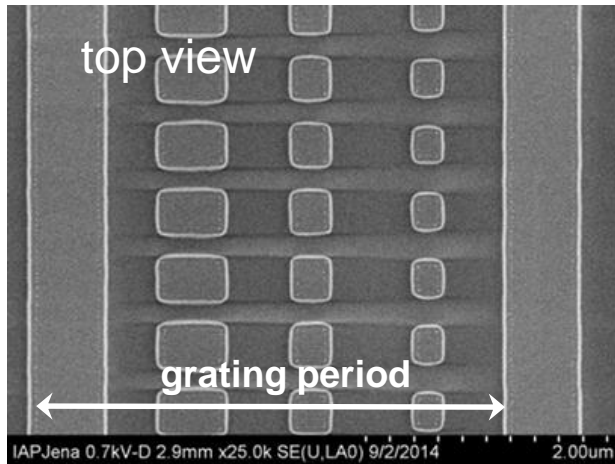
only one lithography step

tailoring of dispersion properties

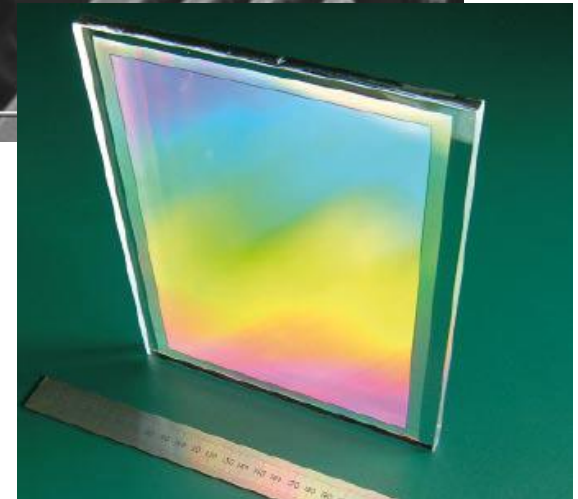
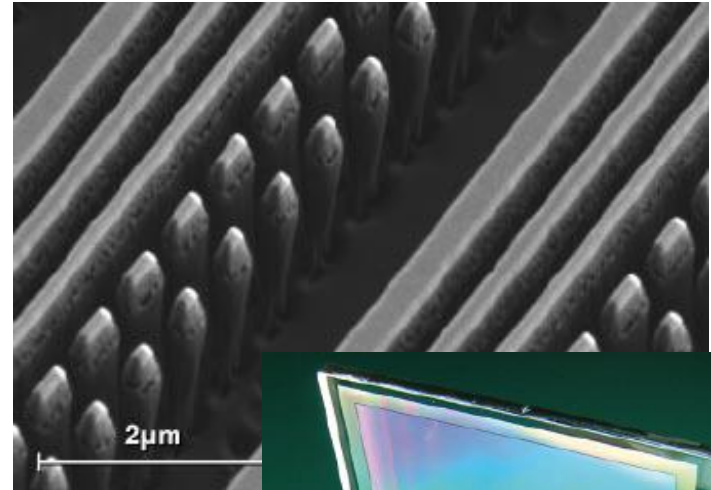


Effective Medium Gratings

FLEX (fluorescence explorer);
[500nm – 800nm]



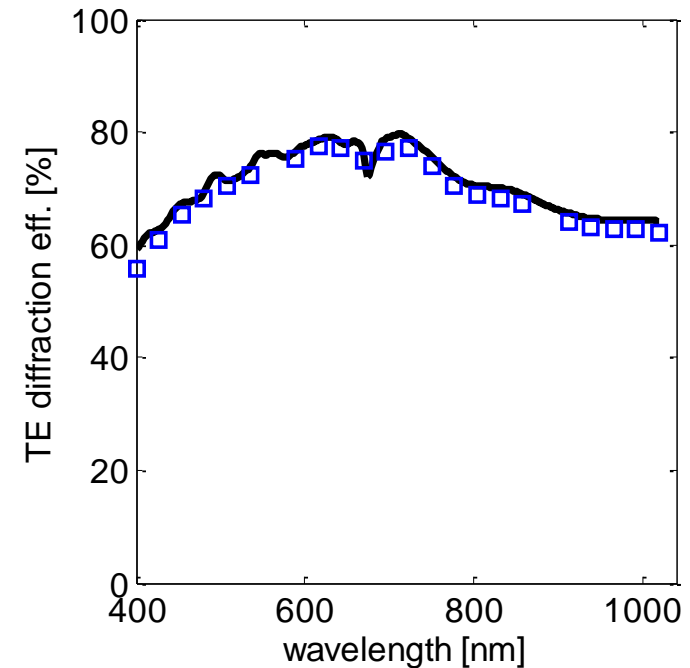
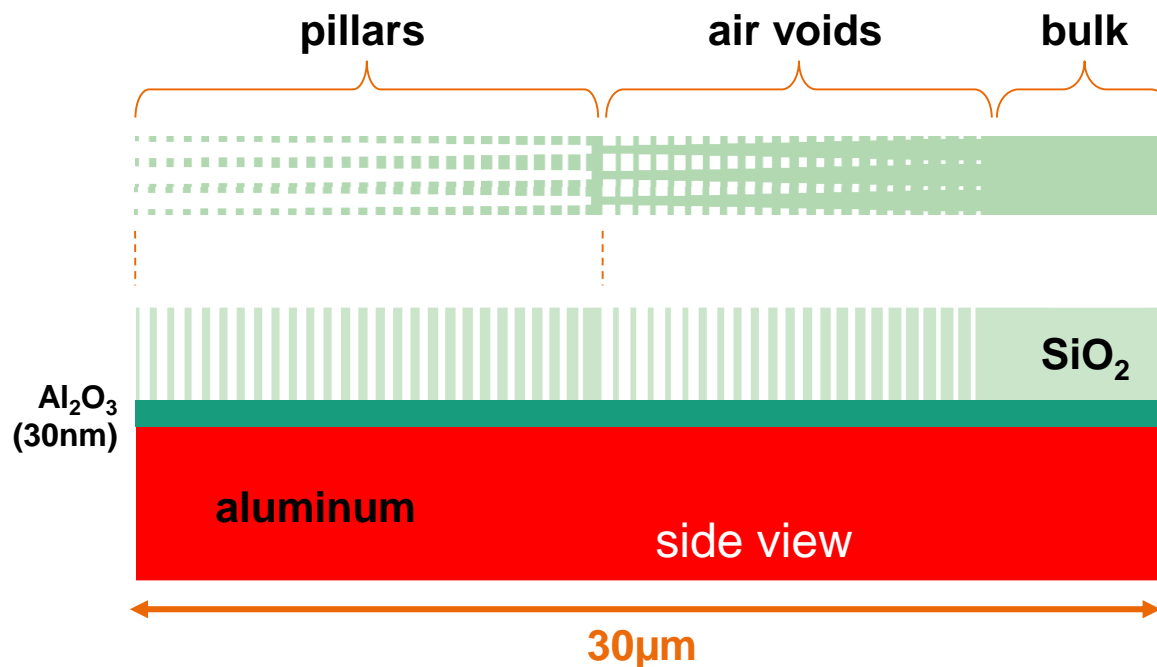
GAIA (global astrometric interferometer for astrophysics); [750nm – 800nm]



Wide-Band Reflection Grating

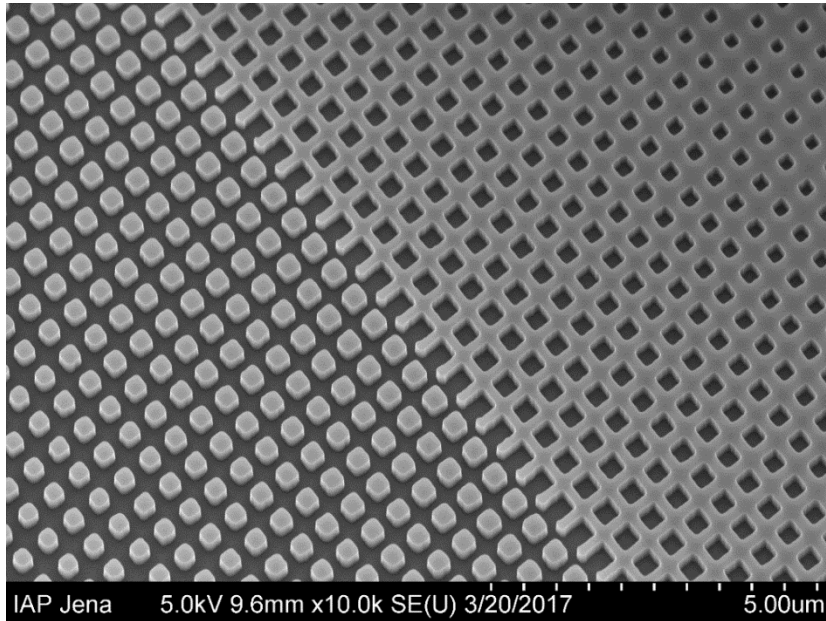
- typical requirements
 - based on a concave grating
 - spectral range: **340nm – 1050nm**
 - AOI: 0.5°
 - period: $30\mu\text{m}$

- effective medium approach**

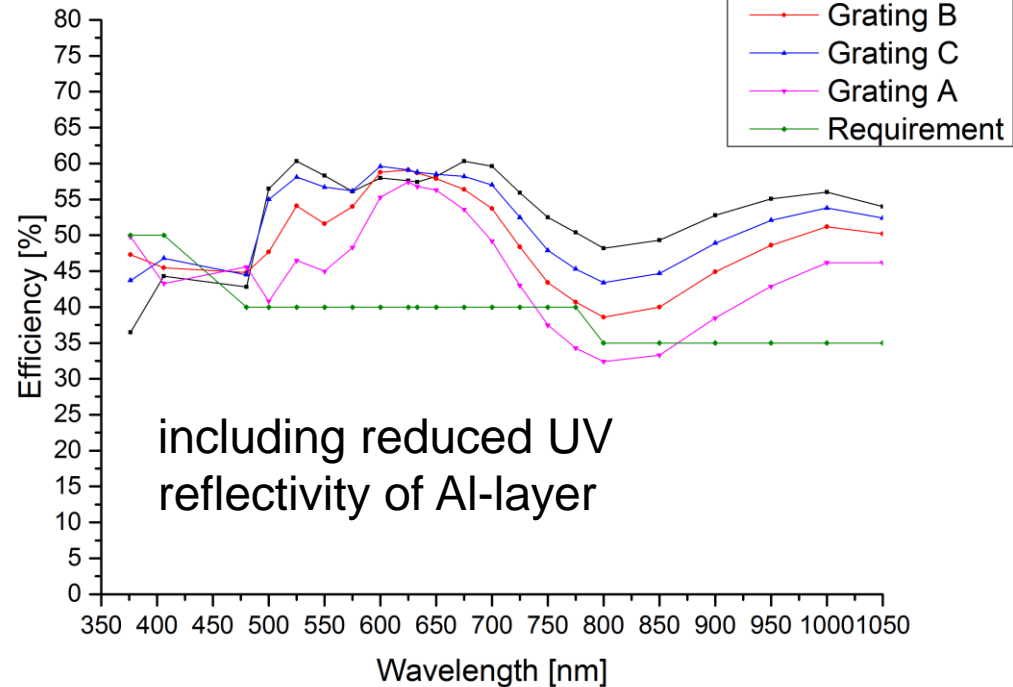


Wide-Band Reflection Grating ...

... realized by E-beam lithography



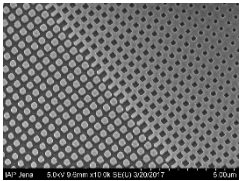
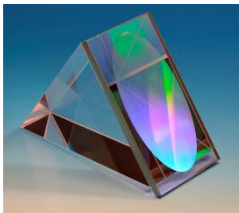
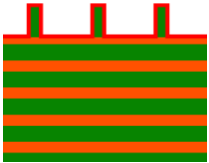
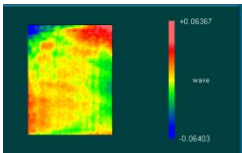
measured diffraction efficiency:



→ very weak spectral dependency of diffraction efficiency



Summary



- Direct write **electron-beam lithography** has a **huge potential** for the realization of high-performance gratings

Sub-period engineering by combining
E-Beam lithography and **Atomic-Layer-Deposition**

To make use of the large flexibility and the advantageous optical properties requires talking with the grating manufacturer **already during the design** of the instrument !!!
(not after PDR...)

- Examples are:
 - **high resolution gratings** with **low polarization sensitivity**
 - **echelle-type gratings** with **integrated cross-disperser**
 - **ultra-wide-band gratings** for lower resolution spectrometers

